

Search Notes

Application/Control No.

10/630,647

Examiner

Nhan T. Tran

Applicant(s)/Patent under
Reexamination

BECK ET AL.

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB) text search - see search history printout	11/17/2006	NT
348/294-324 (text search - see search history printout)	11/17/2006	NT